

**Thermal Resistance**

Symbol	Parameter	Typ.	Max.	Units
$R_{\theta JC}$ (Bottom)	Junction-to-Case ⑧	—	4.4	°C/W
$R_{\theta JC}$ (Top)	Junction-to-Case ⑧	—	50	
$R_{\theta JA}$	Junction-to-Ambient ⑦	—	105	
$R_{\theta JA}$ (<10s)	Junction-to-Ambient ⑦	—	82	

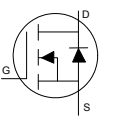
**Static Electrical Characteristics @  $T_J = 25^\circ\text{C}$  (unless otherwise specified)**

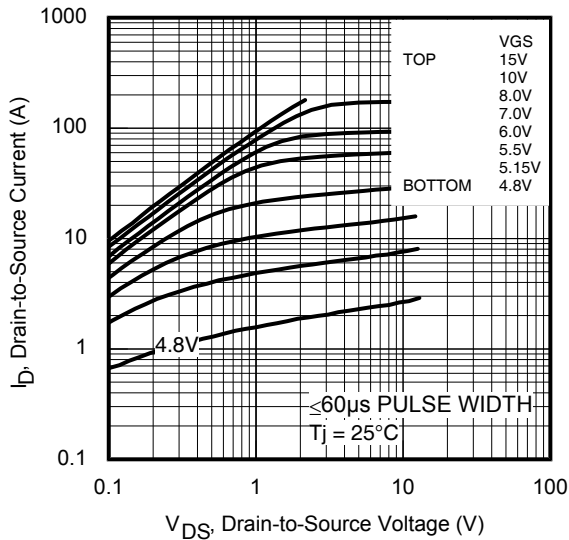
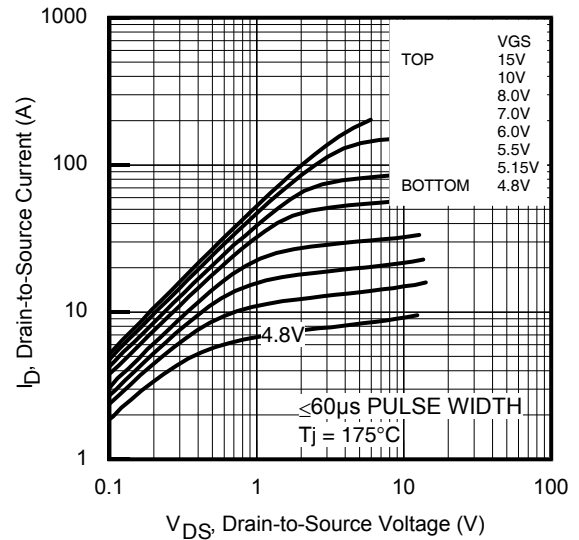
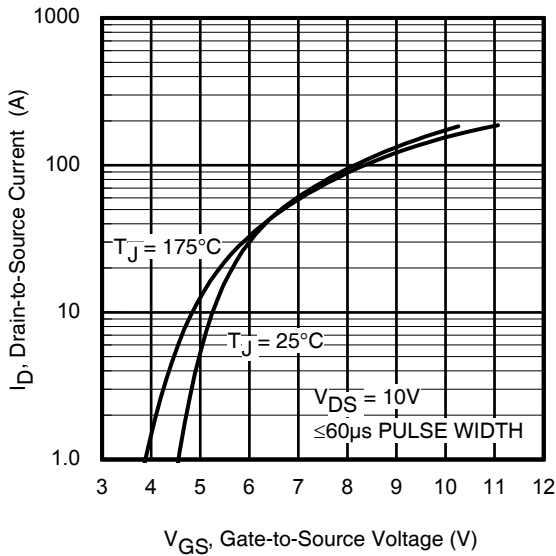
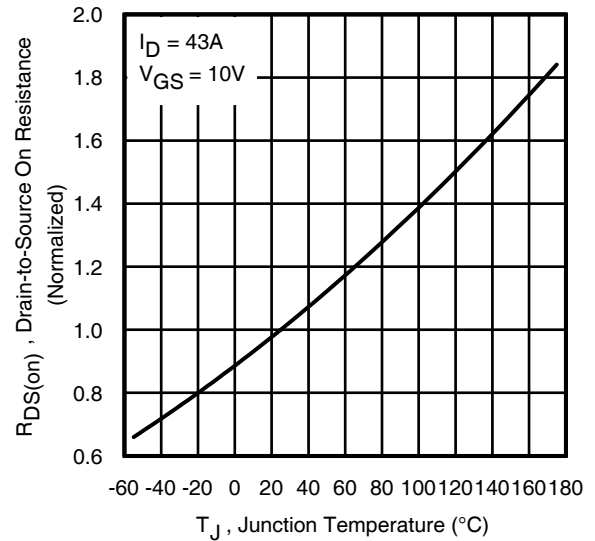
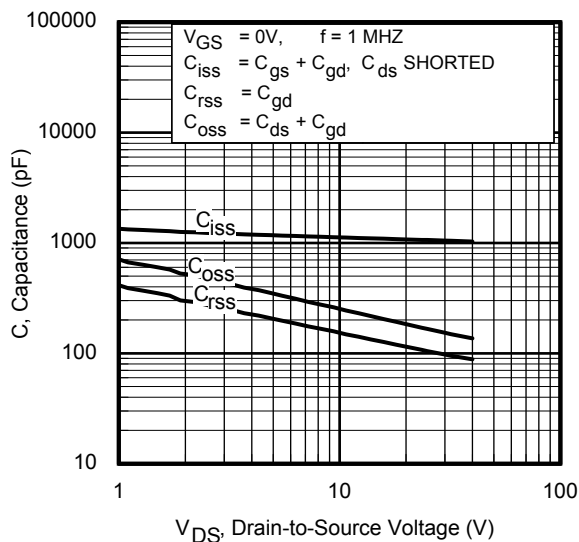
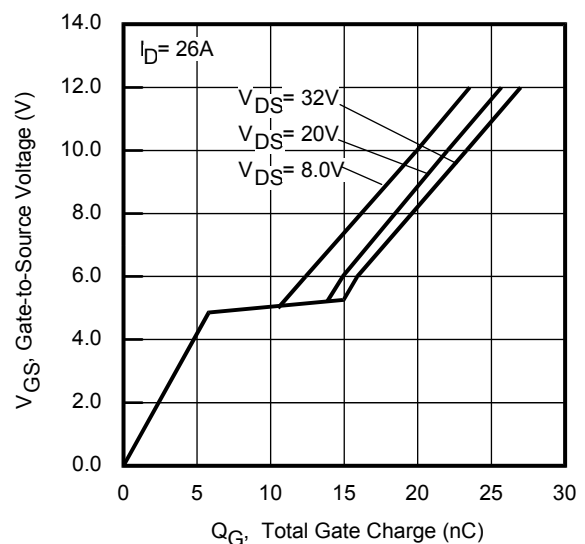
Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	40	—	—	V	$V_{GS} = 0V$ , $I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	37	—	mV/°C	Reference to $25^\circ\text{C}$ , $I_D = 1.0\text{mA}$
$R_{DS(on)}$	Static Drain-to-Source On-Resistance	—	8.0	10	mΩ	$V_{GS} = 10V$ , $I_D = 26A$
$V_{GS(th)}$	Gate Threshold Voltage	2.2	—	3.9	V	$V_{DS} = V_{GS}$ , $I_D = 25\mu A$
$g_{fs}$	Forward Transconductance	56	—	—	S	$V_{DS} = 10V$ , $I_D = 26A$
$R_G$	Internal Gate Resistance	—	1.9	—	Ω	
$I_{DSS}$	Drain-to-Source Leakage Current	—	—	1.0	μA	$V_{DS} = 40V$ , $V_{GS} = 0V$
		—	—	150		$V_{DS} = 40V$ , $V_{GS} = 0V$ , $T_J = 125^\circ\text{C}$
$I_{GSS}$	Gate-to-Source Forward Leakage	—	—	100	nA	$V_{GS} = 20V$
	Gate-to-Source Reverse Leakage	—	—	-100		$V_{GS} = -20V$

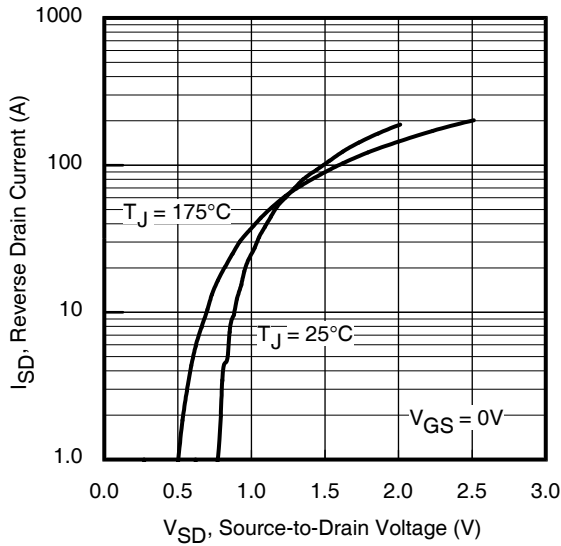
**Dynamic Electrical Characteristics @  $T_J = 25^\circ\text{C}$  (unless otherwise specified)**

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$Q_g$	Total Gate Charge	—	22	33	nC	$I_D = 26A$
$Q_{gs}$	Gate-to-Source Charge	—	6.3	—		$V_{DS} = 20V$
$Q_{gd}$	Gate-to-Drain ("Miller") Charge	—	7.6	—		$V_{GS} = 10V$
$Q_{sync}$	Total Gate Charge Sync. ( $Q_g - Q_{gd}$ )	—	14.4	—		$I_D = 26A$ , $V_{DS} = 0V$ , $V_{GS} = 10V$
$t_{d(on)}$	Turn-On Delay Time	—	9.7	—	ns	$V_{DD} = 26V$
$t_r$	Rise Time	—	71	—		$I_D = 26A$
$t_{d(off)}$	Turn-Off Delay Time	—	11	—		$R_G = 2.7\Omega$
$t_f$	Fall Time	—	19	—		$V_{GS} = 10V$ ④
$C_{iss}$	Input Capacitance	—	1060	—	pF	$V_{GS} = 0V$
$C_{oss}$	Output Capacitance	—	170	—		$V_{DS} = 25V$
$C_{rss}$	Reverse Transfer Capacitance	—	100	—		$f = 1.0\text{MHz}$
$C_{oss \text{ eff. (ER)}}$	Effective Output Capacitance (Energy Related)	—	210	—		$V_{GS} = 0V$ , $V_{DS} = 0V$ to $32V$ ⑥
$C_{oss \text{ eff. (TR)}}$	Effective Output Capacitance (Time Related)	—	250	—		$V_{GS} = 0V$ , $V_{DS} = 0V$ to $32V$ ⑤

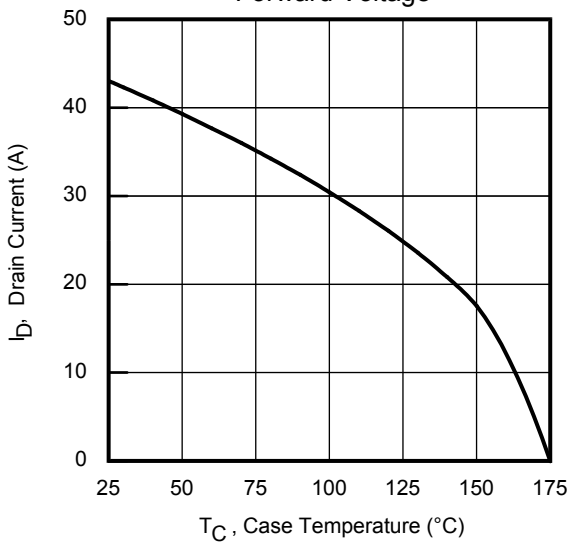
**Diode Characteristics**

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$I_S$	Continuous Source Current (Body Diode)	—	—	43	A	MOSFET symbol showing the integral reverse p-n junction diode. 
$I_{SM}$	Pulsed Source Current (Body Diode) ①	—	—	180	A	
$V_{SD}$	Diode Forward Voltage	—	—	1.3	V	$T_J = 25^\circ\text{C}$ , $I_S = 26A$ , $V_{GS} = 0V$ ④
$dv/dt$	Peak Diode Recovery	—	8.2	—	V/ns	$T_J = 175^\circ\text{C}$ , $I_S = 26A$ , $V_{DS} = 40V$ ③
$t_{rr}$	Reverse Recovery Time	—	18	—	ns	$T_J = 25^\circ\text{C}$
		—	19	—		$T_J = 125^\circ\text{C}$
$Q_{rr}$	Reverse Recovery Charge	—	9.6	—	nC	$T_J = 25^\circ\text{C}$
		—	11	—		$T_J = 125^\circ\text{C}$
$I_{RRM}$	Reverse Recovery Current	—	0.89	—	A	$T_J = 25^\circ\text{C}$

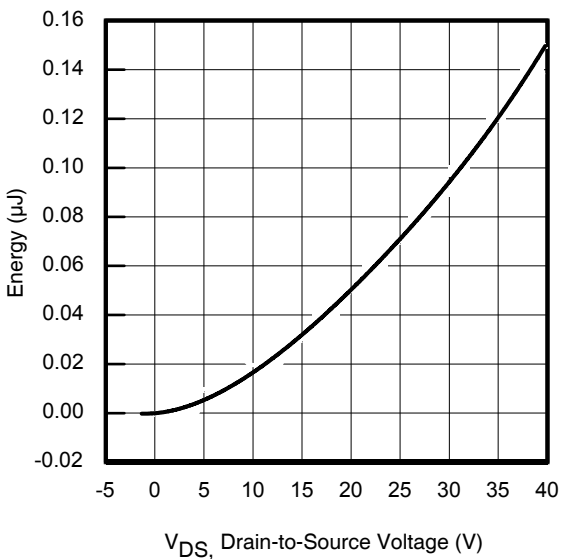

**Fig. 1** Typical Output Characteristics

**Fig. 2** Typical Output Characteristics

**Fig. 3** Typical Transfer Characteristics

**Fig. 4** Normalized On-Resistance vs. Temperature

**Fig 5.** Typical Capacitance vs. Drain-to-Source Voltage

**Fig 6.** Typical Gate Charge vs. Gate-to-Source Voltage



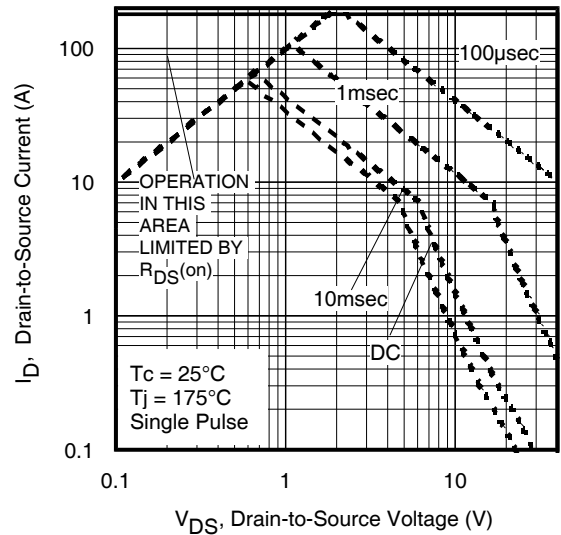
**Fig. 7** Typical Source-to-Drain Diode Forward Voltage



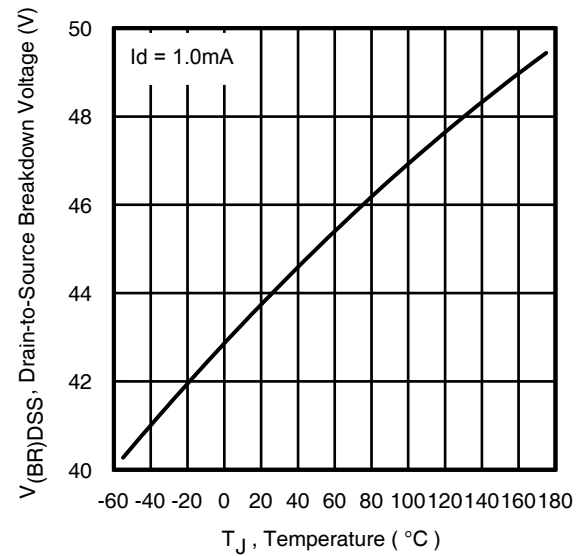
**Fig 9.** Maximum Drain Current vs. Case Temperature



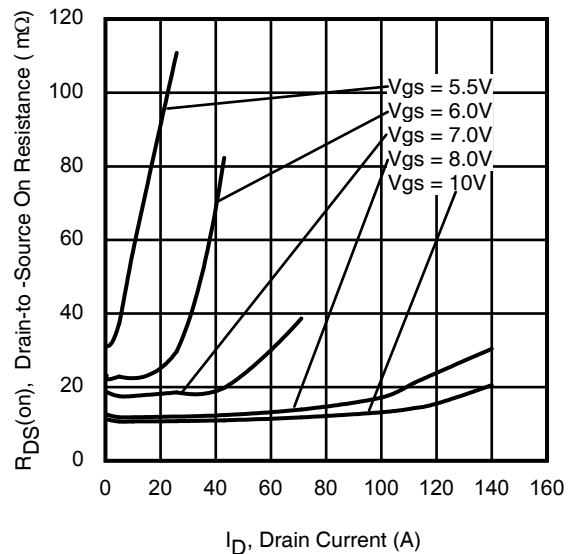
**Fig 11.** Typical  $C_{oss}$  Stored Energy



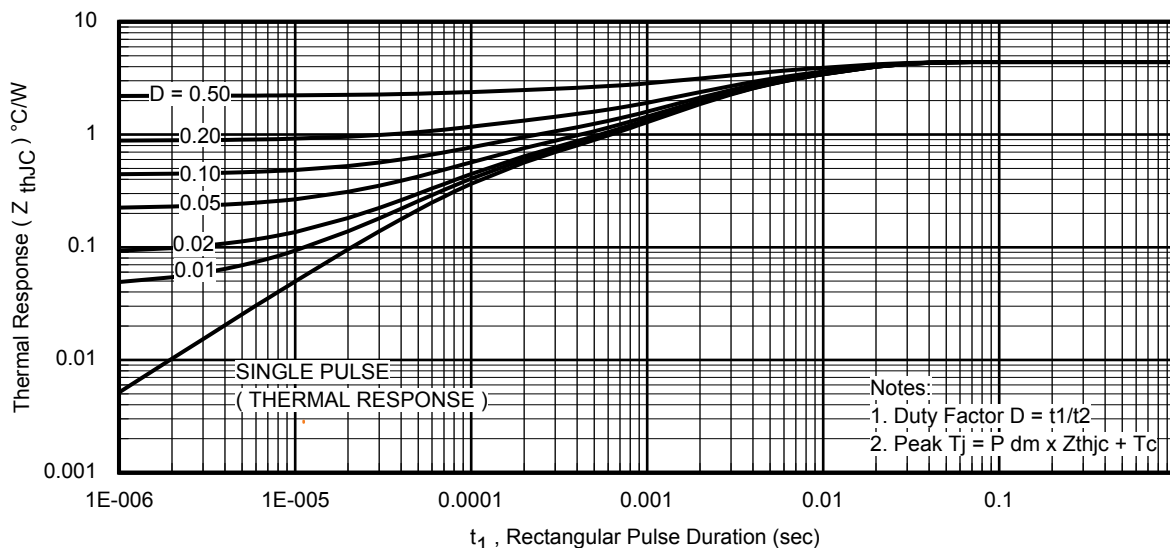
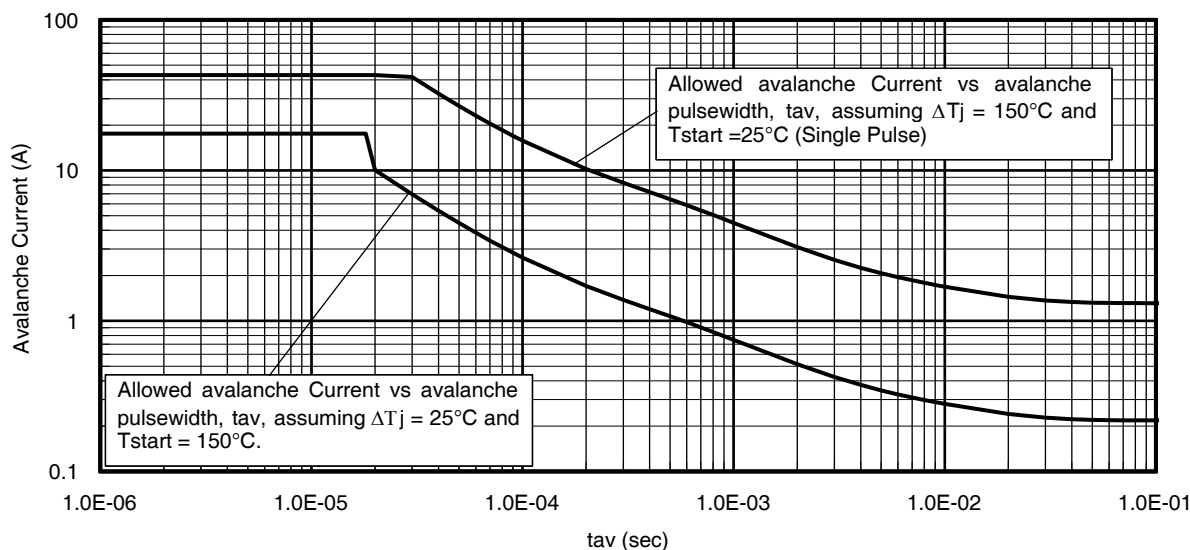
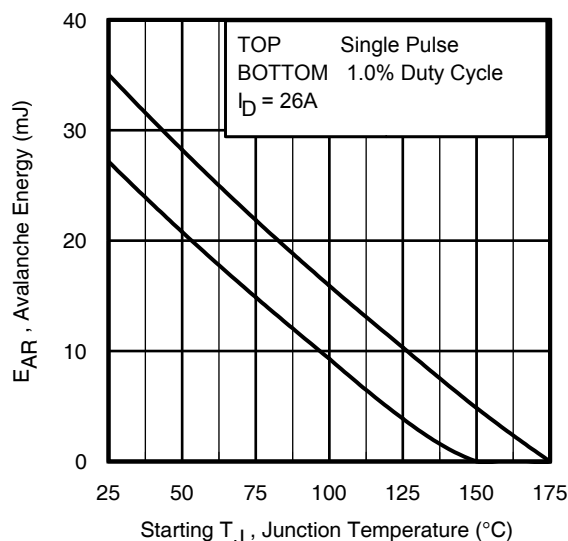
**Fig 8.** Maximum Safe Operating Area



**Fig 10.** Drain-to-Source Breakdown Voltage



**Fig 12.** Typical On-Resistance vs. Drain Current


**Fig 13.** Maximum Effective Transient Thermal Impedance, Junction-to-Case

**Fig 14.** Typical Avalanche Current vs. Pulse Width

**Fig 15.** Maximum Avalanche Energy vs. Temperature

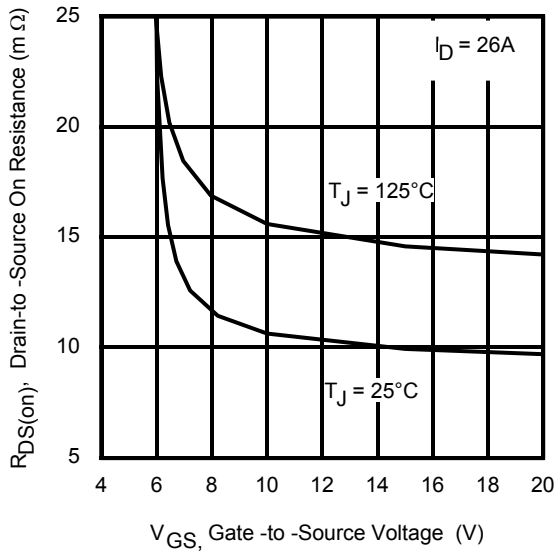
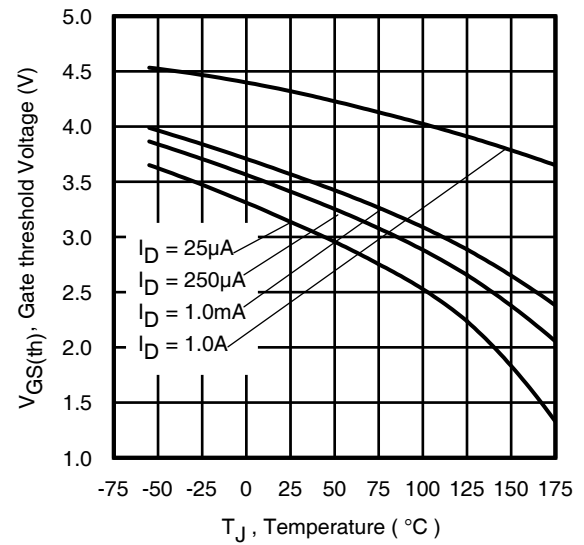
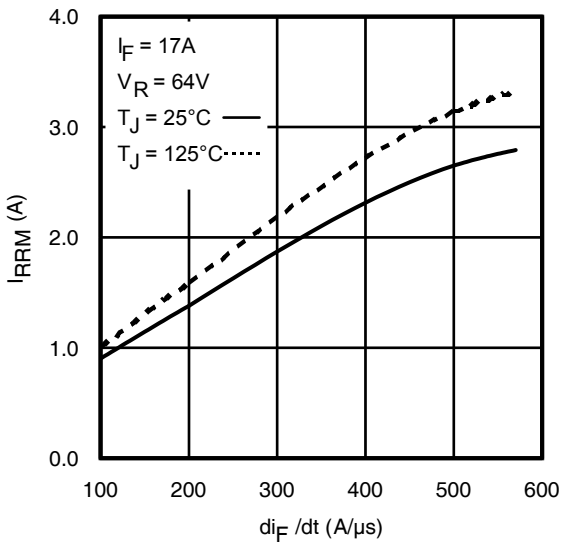
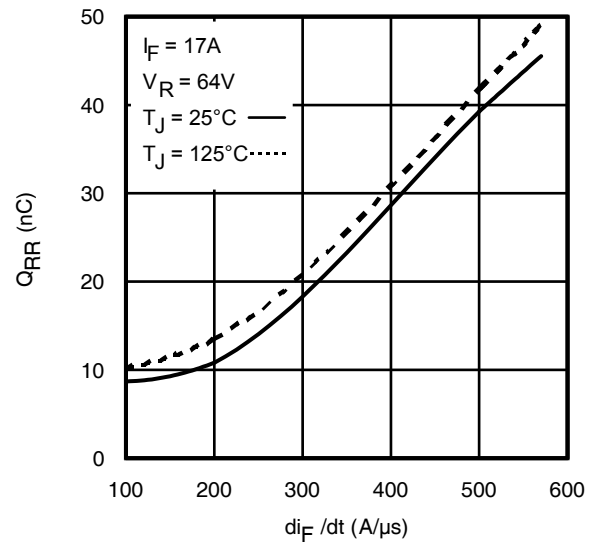
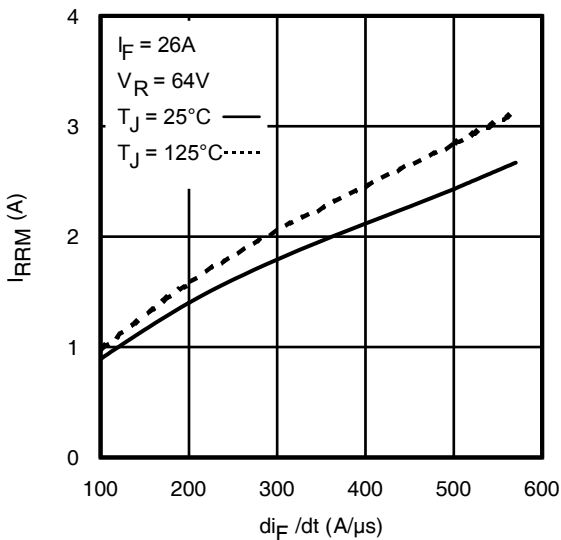
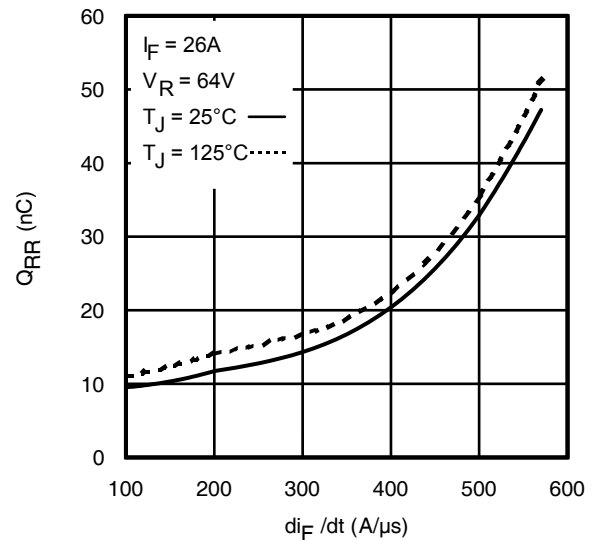
**Notes on Repetitive Avalanche Curves, Figures 14, 15:**  
**(For further info, see AN-1005 at [www.irf.com](http://www.irf.com))**

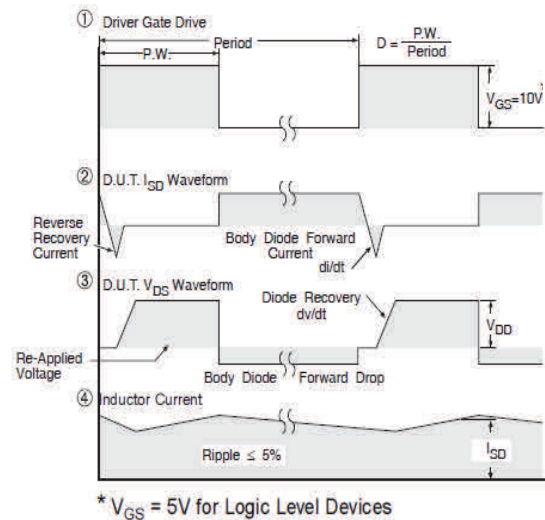
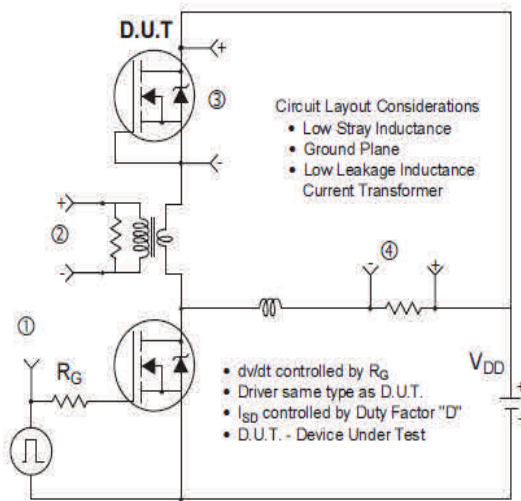
1. Avalanche failures assumption:  
Purely a thermal phenomenon and failure occurs at a temperature far in excess of  $T_{jmax}$ . This is validated for every part type.
2. Safe operation in Avalanche is allowed as long as  $T_{jmax}$  is not exceeded.
3. Equation below based on circuit and waveforms shown in Figures 16a, 16b.
4.  $P_{D(ave)}$  = Average power dissipation per single avalanche pulse.
5.  $BV$  = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
6.  $I_{av}$  = Allowable avalanche current.
7.  $\Delta T$  = Allowable rise in junction temperature, not to exceed  $T_{jmax}$  (assumed as 25°C in Figure 14, 15).  
 $t_{av}$  = Average time in avalanche.  
 $D$  = Duty cycle in avalanche =  $t_{av} \cdot f$   
 $Z_{thJC}(D, t_{av})$  = Transient thermal resistance, see Figures 13)

$$P_{D(ave)} = 1/2 (1.3 \cdot BV \cdot I_{av}) = \Delta T / Z_{thJC}$$

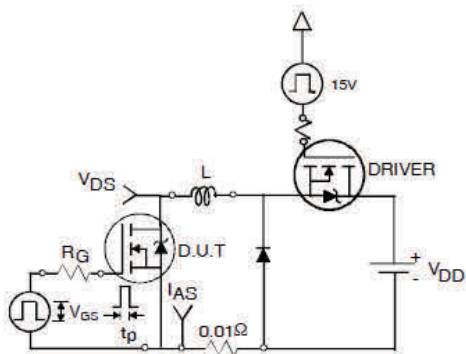
$$I_{av} = 2\Delta T / [1.3 \cdot BV \cdot Z_{th}]$$

$$E_{AS(AR)} = P_{D(ave)} \cdot t_{av}$$

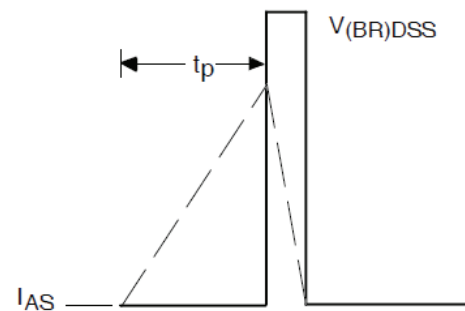

**Fig 16.** Typical On-Resistance vs. Gate Voltage

**Fig 17.** Threshold Voltage vs. Temperature

**Fig. 18 -** Typical Recovery Current vs.  $di_F/dt$ 

**Fig. 19 -** Typical Stored Charge vs.  $di_F/dt$ 

**Fig. 20 -** Typical Recovery Current vs.  $di_F/dt$ 

**Fig. 21 -** Typical Stored Charge vs.  $di_F/dt$



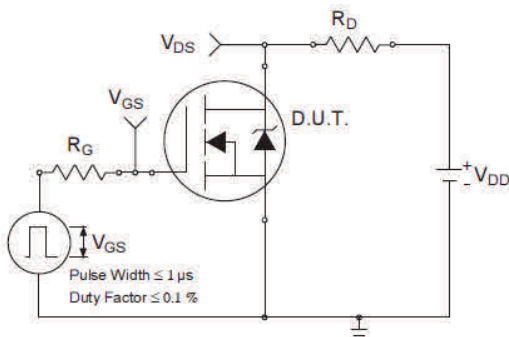
**Fig 22.** Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs



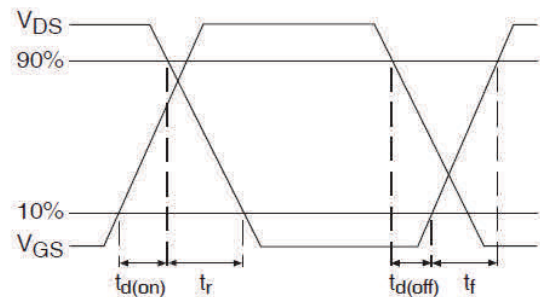
**Fig 22a.** Unclamped Inductive Test Circuit



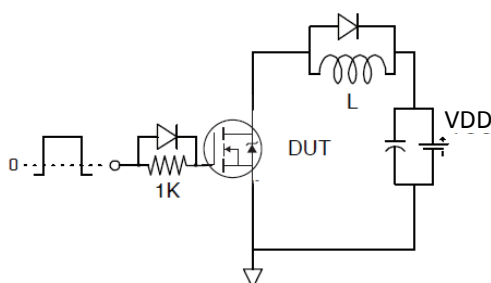
**Fig 22b.** Unclamped Inductive Waveforms



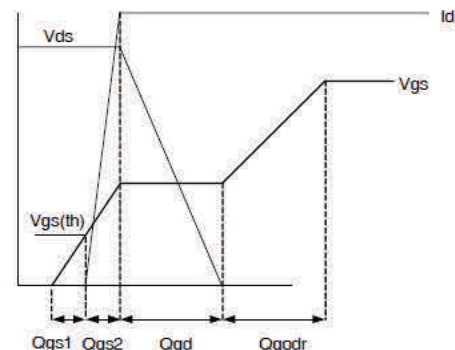
**Fig 23a.** Switching Time Test Circuit



**Fig 23b.** Switching Time Waveforms

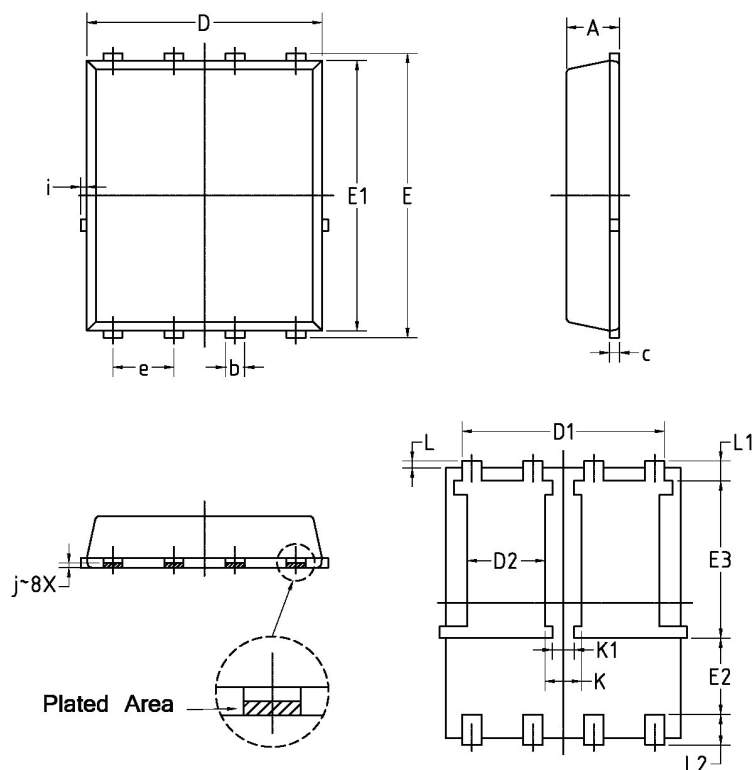


**Fig 24a.** Gate Charge Test Circuit



**Fig 24b.** Gate Charge Waveform

## Dual PQFN 5x6 Package Details

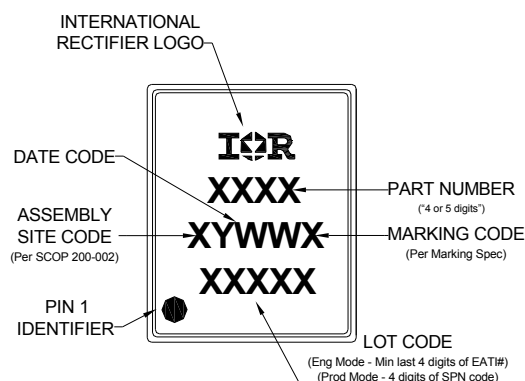


SYMBOL	COMMON			
	MM		INCH	
	MIN.	MAX.	MIN.	MAX.
A	1.00	1.20	0.039	0.047
b	0.30	0.50	0.012	0.020
c	0.203 BSC		0.008 BSC	
D	4.80	5.00	0.189	0.197
D1	4.06	4.36	0.160	0.172
D2	1.47	1.77	0.058	0.070
E	5.90	6.20	0.232	0.244
E1	5.65	5.85	0.222	0.230
E2	1.45	—	0.057	—
E3	3.20	3.50	0.126	0.138
e	1.27 BSC		0.05 BSC	
L	0.05	0.25	0.002	0.010
L1	0.325	0.525	0.013	0.021
L2	0.500	0.800	0.020	0.031
i	—	0.20	—	0.008
K	0.61	0.91	0.024	0.036
K1	0.31	0.60	0.012	0.024
j	0.1015 BSC		0.004 BSC	

For more information on board mounting, including footprint and stencil recommendation, please refer to application note AN-1136: <http://www.irf.com/technical-info/appnotes/an-1136.pdf>

For more information on package inspection techniques, please refer to application note AN-1154: <http://www.irf.com/technical-info/appnotes/an-1154.pdf>

## Dual PQFN 5x6 Part Marking



Note: For the most current drawing please refer to IR website at <http://www.irf.com/package/>

**Qualification Information<sup>†</sup>**

Qualification Level		Automotive (per AEC-Q101)	
		Comments: This part number(s) passed Automotive qualification. IR's Industrial and Consumer qualification level is granted by extension of the higher Automotive level.	
Moisture Sensitivity Level		Dual PQFN 5mm x 6mm	MSL1
ESD	Human Body Model	Class H1A (+/- 500V) <sup>††</sup>	
		AEC-Q101-001	
	Charged Device Model	Class C5 (+/- 1000V) <sup>††</sup>	
		AEC-Q101-005	
RoHS Compliant		Yes	

† Qualification standards can be found at International Rectifier's web site: <http://www.irf.com/>

†† Highest passing voltage.

**Notes:**

- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Limited by  $T_{Jmax}$ , starting  $T_J = 25^{\circ}C$ ,  $L = 110\mu H$ ,  $R_G = 50\Omega$ ,  $I_{AS} = 50A$ ,  $V_{GS} = 10V$ .
- ③  $I_{SD} \leq 50A$ ,  $di/dt \leq 650A/\mu s$ ,  $V_{DD} \leq V_{(BR)DSS}$ ,  $T_J \leq 175^{\circ}C$ .
- ④ Pulse width  $\leq 400\mu s$ ; duty cycle  $\leq 2\%$ .
- ⑤  $C_{oss\ eff.\ (TR)}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$ .
- ⑥  $C_{oss\ eff.\ (ER)}$  is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$ .
- ⑦ When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994: <http://www.irf.com/technical-info/appnotes/an-994.pdf>
- ⑧  $R_{\theta}$  is measured at  $T_J$  of approximately  $90^{\circ}C$ .
- ⑨ This value determined from sample failure population, starting  $T_J = 25^{\circ}C$ ,  $L = 110\mu H$ ,  $R_G = 50\Omega$ ,  $I_{AS} = 50A$ ,  $V_{GS} = 10V$ .



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